

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 10/094,580
Priority Filing Date March 6, 2002
 Inventor Cem Basceri et al.
 Assignee Micron Technology, Inc.
Priority Group Art Unit 2818
Priority Examiner David Nhu
 Attorney Docket No. MI22-2407
 Title: Plasma Enhanced Chemical Vapor Deposition Method of Forming a
 Titanium Silicide Comprising Layer

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98


In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 10/094,580, filed March 6, 2002. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. § 1.98(d) and MPEP § 609(2).

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 9-17-03

By: 
 Mark S. Matkin
 Reg. No. 32,268

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2407		PRIORITY SERIAL NO.: 10/094,580	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Cem Basceri et al.			
				PRIORITY FILING DATE: March 6, 2002		PRIORITY GROUP ART UNIT: 2818	

U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,957,777	09/18/90	Ilderem et al.			
	AB	5,240,739	09/31/93	Doan et al.			
	AC	5,252,518	10/12/93	Sandhu et al.			
	AD	5,278,100	01/11/94	Doan et al.			
	AE	5,344,792	09/06/94	Sandhu et al.			
	AF	5,376,405	12/27/94	Doan et al.			
	AG	5,976,976	11/02/99	Doan et al.			
	AH	6,019,839	02/01/00	Achutharaman et al.			
	AI	6,086,442	07/11/00	Sandhu et al.			

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AM		
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U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,245,674 B1	06/12/01	Sandhu			
	AB	6,255,216 B1	07/03/01	Doan et al.			
	AC	6,444,556 B2	09/03/02	Sharan et al.			
	AD	6,472,756 B2	10/29/02	Doan et al.			
	AE	6,554,910 B1	04/29/03	Sandhu et al.			
	AF	09/944,903	08/30/01	Derraa et al. (as filed)			
	AG	09/945,065	08/30/01	Derraa et al. (as filed)			
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	AI						

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